Appl. No. 10/650,505 Supplemental Amdt. Dated July 13, 2005 Reply to Office Action of June 3, 2005 Attorney Docket No. 81872.0051 Customer No.: 26021

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 1. (Withdrawn) A dry etching apparatus, comprising:
- a chamber;
- an RF electrode provided inside said chamber; and
- a plate provided in parallel or nearly parallel with said RF electrode to cover a substrate to be etched, placed on said RF electrode directly or through a tray,

wherein said plate is provided with a planar or nearly planar obstacle that inhibits a part of gas and plasma from passing through said plate.

- 2. (Withdrawn) The dry etching apparatus according to Claim 1, wherein a member forming said obstacle is provided with a number of opening portions.
- 3. (Withdrawn) The dry etching apparatus according to Claim 2, wherein an open area ratio of said obstacle is 5 to 40%.
- 4. (Withdrawn) The dry etching apparatus according to Claim 1, wherein said obstacle comprises a combination of a plurality of obstacle forming members, and an opening portion is provided between neighboring obstacle forming members.
- 5. (Withdrawn) The dry etching apparatus according to Claim 4, wherein an open area ratio of said obstacle is 5 to 40%.

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- 6. (Withdrawn) The dry etching apparatus according to Claim 1, wherein said obstacle comprises a plurality of long members aligned with a clearance in between.
- 7. (Withdrawn) The dry etching apparatus according to Claim 6, wherein said long member is a bar-shaped or sheet member.
- 8. (Withdrawn) The dry etching apparatus according to Claim 6, wherein said obstacle comprises a mesh woven by crossing said plurality of long members over and under with each other.
- 9. (Withdrawn) The dry etching apparatus according to Claim 1, wherein said obstacle comprises a plurality of obstacles of a laminated structure.
- 10. (Withdrawn) The dry etching apparatus according to Claim 9, wherein said obstacle comprises a member formed by laminating a plurality of long members aligned with a clearance in between, in different directions.
- 11. (Withdrawn) The dry etching apparatus according to Claim 1, wherein said obstacle is made of one kind or a combination of two or more kinds selected from a group consisting of materials (a), (b), and (c) as follows:
 - (a) a glass-based material:
 - (b) a metal material; and
 - (c) a resin material.
- 12. (Withdrawn) The dry etching apparatus according to Claim 11, wherein said metal material is an aluminum-based material.

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13. (Original) A dry etching method for forming fine textures on a surface of a substrate to be etched, said dry etching method comprising:

placing a substrate to be etched on an RF electrode provided inside a chamber, directly or through a tray; and

covering said substrate to be etched with a plate,

wherein said plate is provided with a planar or nearly planar obstacle that inhibits a part of gas and plasma from passing through said plate.

- 14. (Currently amended) The dry etching method according to Claim 13, wherein said substrate to be etched is made of any one of silicon, glass, metal, plastic, and resin.
- 15. (Original) The dry etching method according to Claim 13, wherein said plate covers said substrate to be etched while securing a distance of 5 mm to 30 mm.
 - 16. (Withdrawn) A dry etching apparatus, comprising: a chamber;

an RF electrode provided inside said chamber; and

a plate provided with a number of opening portions and provided in parallel or nearly parallel with said RF electrode to cover a substrate to be etched, placed on said RF electrode directly or through a tray,

wherein said plate is structured in such a manner that a surface and a back surface are reversed.

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- 17. (Withdrawn) The dry etching apparatus according to Claim 16, wherein the surface and the back surface of said plate are of substantially a same shape.
 - 18. (Original) A dry etching method, comprising:

placing a substrate to be etched on an RF electrode provided inside a chamber, directly or through a tray; and

covering said substrate to be etched with a plate provided with a number of opening portions,

wherein fine textures are formed on a surface of said substrate to be etched and said plate is cleaned on a surface side concurrently.

- 19. (Original) The dry etching method according to Claim 18, wherein said dry etching method is a reactive ion etching method.
- 20. (Original) The dry etching method according to Claim 18, wherein a substrate to be etched next is placed with a surface and a back surface of said plate being reversed after said plate is cleaned on the surface side, and fine textures are formed on a surface of said substrate to be etched next.
- 21. (Withdrawn) A cleaning method adopted in a dry etching apparatus for cleaning a surface of a plate, said cleaning method comprising:

carrying out a substrate from a chamber;

placing a plate provided with a number of opening portions inside said chamber; and

introducing an etching gas inside said chamber.

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22. (New) The dry etching method according to Claim 13, wherein said substrate to be etched is made of any one of glass, metal, plastic, and resin.